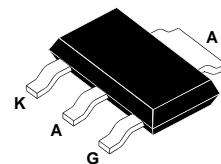


## SENSITIVE GATE SCR

### FEATURES

- $I_{T(RMS)} = 1.4A$
- $V_{DRM} = 200V$  to  $800V$
- Low  $I_{GT} < 200 \mu A$



**SOT223**  
(Plastic)

### DESCRIPTION

The X02xxxN series of SCRs uses a high performance TOP GLASS PNPN technology. These parts are intended for general purpose high volume applications using surface mount technology.

### ABSOLUTE RATINGS (limiting values)

Symbol	Parameter	Value	Unit
$I_{T(RMS)}$ *	RMS on-state current (180° conduction angle)	$T_{tab}= 90^\circ C$	1.4
		$T_a= 75^\circ C$	1.0
$I_{T(AV)}$ *	Mean on-state current (180° conduction angle)	$T_{tab}= 90^\circ C$	0.9
		$T_a= 75^\circ C$	0.64
$I_{TSM}$	Non repetitive surge peak on-state current ( $T_j$ initial = $25^\circ C$ )	$t_p = 8.3$ ms	25
		$t_p = 10$ ms	22.5
$I^2t$	$I^2t$ Value for fusing	$t_p = 10$ ms	$A^2s$
$dl/dt$	Critical rate of rise of on-state current $I_G = 10$ mA $di_G/dt = 0.1$ A/ $\mu s$ .	30	$A/\mu s$
$T_{stg}$ $T_j$	Storage and operating junction temperature range	-40, +150 -40, +125	$^\circ C$
$T_l$	Maximum lead temperature for soldering during 10s	260	$^\circ C$

\* : With 5cm<sup>2</sup> copper ( $e=35\mu m$ ) surface under tab.

Symbol	Parameter	Voltage				Unit
		B	D	M	N	
$V_{DRM}$ $V_{RRM}$	Repetitive peak off-state voltage $T_j = 125^\circ C$ $R_{GK} = 1K\Omega$	200	400	600	800	V

## X02xxxN

### THERMAL RESISTANCES

Symbol	Parameter	Value	Unit
R <sub>th(j-a)</sub>	Junction to ambient *	60	°C/W
R <sub>th(j-t)</sub>	Junction to tab for DC	25	°C/W

\* : With 5cm<sup>2</sup> copper ( $e=35\mu m$ ) surface under tab.

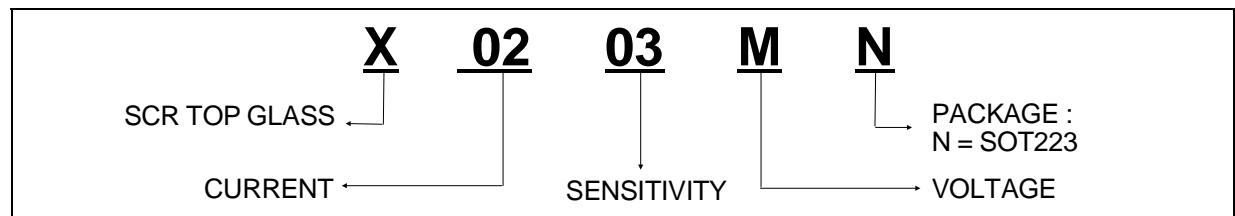
### GATE CHARACTERISTICS (maximum values)

$$P_G(AV) = 0.2 \text{ W} \quad P_{GM} = 3 \text{ W} \quad (t_p = 20 \mu\text{s}) \quad I_{GM} = 1.2 \text{ A} \quad (t_p = 20 \mu\text{s})$$

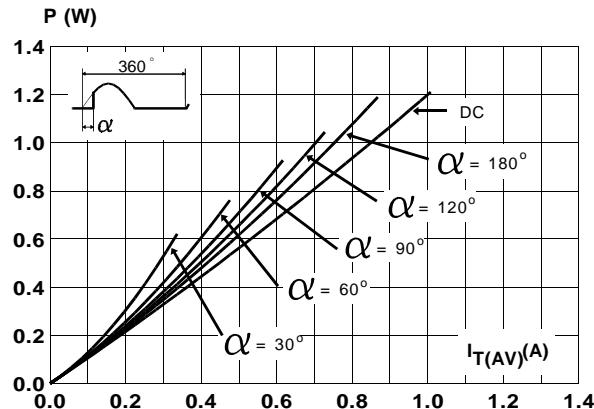
### ELECTRICAL CHARACTERISTICS

Symbol	Test Conditions	Sensitivity			Unit		
		02	03	05			
I <sub>GT</sub>	V <sub>D</sub> =12V (DC) R <sub>L</sub> =140Ω	T <sub>j</sub> = 25°C	MIN		20	20	μA
			MAX	200	200	50	
V <sub>GT</sub>	V <sub>D</sub> =12V (DC) R <sub>L</sub> =140Ω	T <sub>j</sub> = 25°C	MAX	0.8		V	
V <sub>GD</sub>	V <sub>D</sub> =V <sub>DRM</sub> R <sub>L</sub> =3.3kΩ R <sub>GK</sub> = 1 KΩ	T <sub>j</sub> = 125°C	MIN	0.1		V	
V <sub>RGM</sub>	I <sub>RG</sub> =10μA	T <sub>j</sub> = 25°C	MIN	8		V	
t <sub>gd</sub>	V <sub>D</sub> =V <sub>DRM</sub> I <sub>TM</sub> = 3 × I <sub>T(AV)</sub> dI <sub>G</sub> /dt = 0.1A/μs I <sub>G</sub> = 10mA	T <sub>j</sub> = 25°C	TYP	0.5		μs	
I <sub>H</sub>	I <sub>T</sub> = 50mA R <sub>GK</sub> = 1 KΩ	T <sub>j</sub> = 25°C	MAX	5		mA	
I <sub>L</sub>	I <sub>G</sub> =1mA R <sub>GK</sub> = 1 KΩ	T <sub>j</sub> = 25°C	MAX	6		mA	
V <sub>TM</sub>	I <sub>TM</sub> = 2.8A t <sub>p</sub> = 380μs	T <sub>j</sub> = 25°C	MAX	1.5		V	
I <sub>DRM</sub> I <sub>RRM</sub>	V <sub>D</sub> = V <sub>DRM</sub> R <sub>GK</sub> = 1 KΩ V <sub>R</sub> = V <sub>RRM</sub>	T <sub>j</sub> = 25°C	MAX	5		μA	
		T <sub>j</sub> = 110°C	MAX	200		μA	
dV/dt	V <sub>D</sub> =67%V <sub>DRM</sub> R <sub>GK</sub> = 1 KΩ	T <sub>j</sub> = 110°C	TYP	15	20	15	V/μs
t <sub>q</sub>	I <sub>TM</sub> = 3 × I <sub>T(AV)</sub> V <sub>R</sub> =35V dI/dt=10A/μs t <sub>p</sub> =100μs dV/dt=2V/μs V <sub>D</sub> = 67%V <sub>DRM</sub> R <sub>GK</sub> = 1 KΩ	T <sub>j</sub> = 110°C	MAX	100		μs	

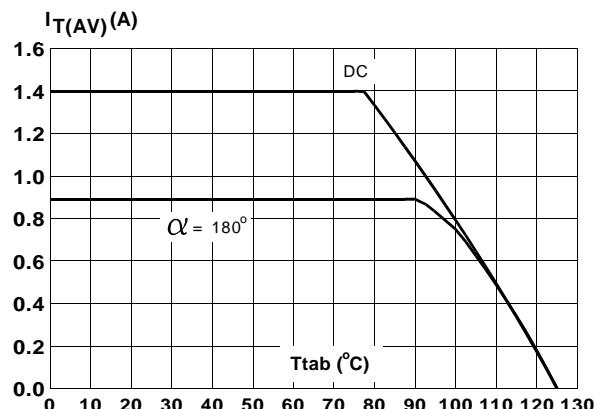
### ORDERING INFORMATION



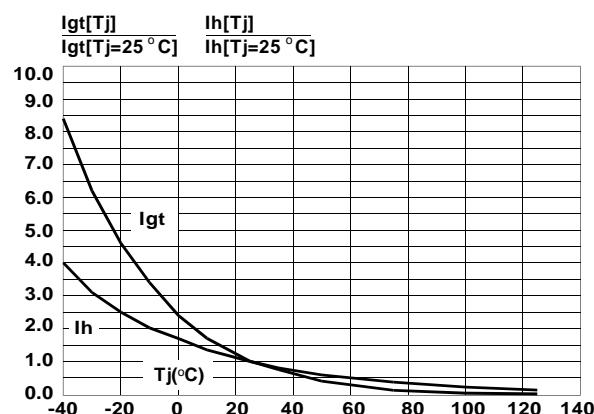
**Fig.1 :** Maximum average power dissipation versus average on-state current.



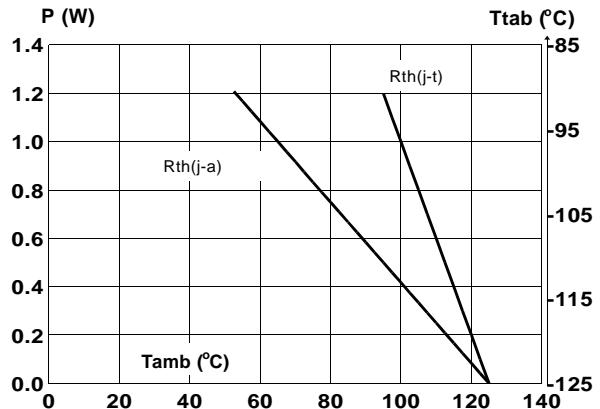
**Fig.3 :** Average on-state current versus tab temperature.



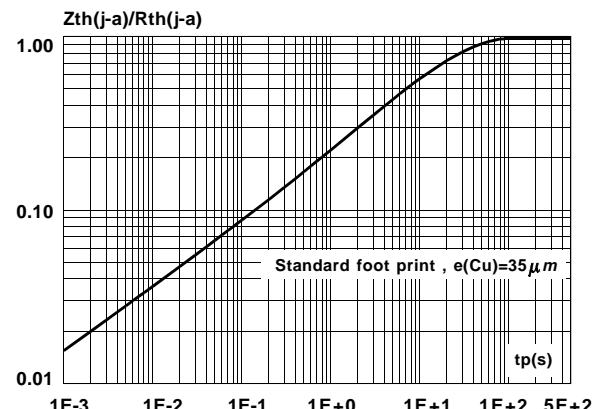
**Fig.5 :** Relative variation of gate trigger current and holding current versus junction temperature.



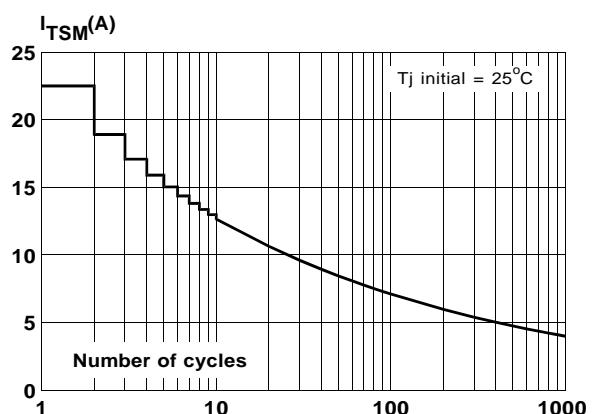
**Fig.2 :** Correlation between maximum average power dissipation and maximum allowable temperature (Tamb and Ttab).



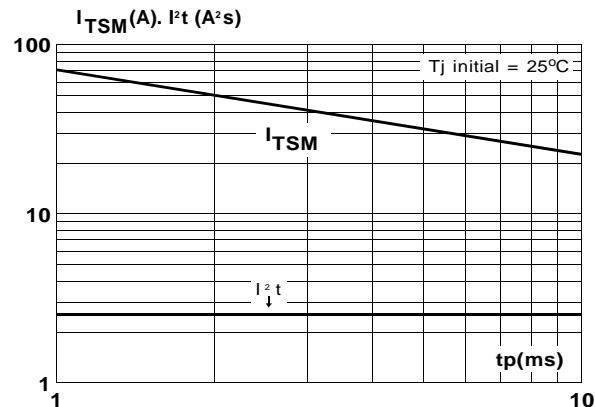
**Fig.4 :** Relative variation of thermal impedance junction to ambient versus pulse duration.



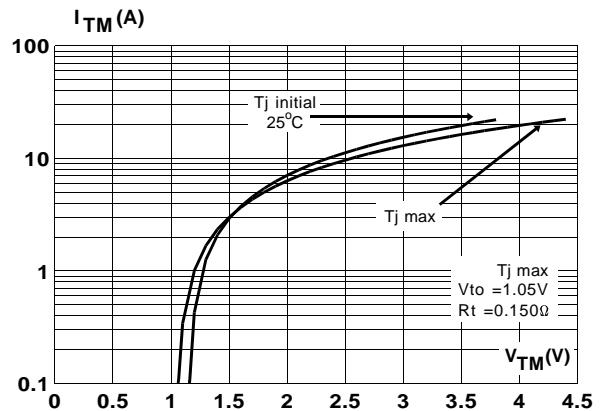
**Fig.6 :** Non repetitive surge peak on-state current versus number of cycles.



**Fig.7 :** Non repetitive surge peak on-state current for a sinusoidal pulse with width :  $tp \leq 10\text{ms}$ , and corresponding value of  $I^2t$ .

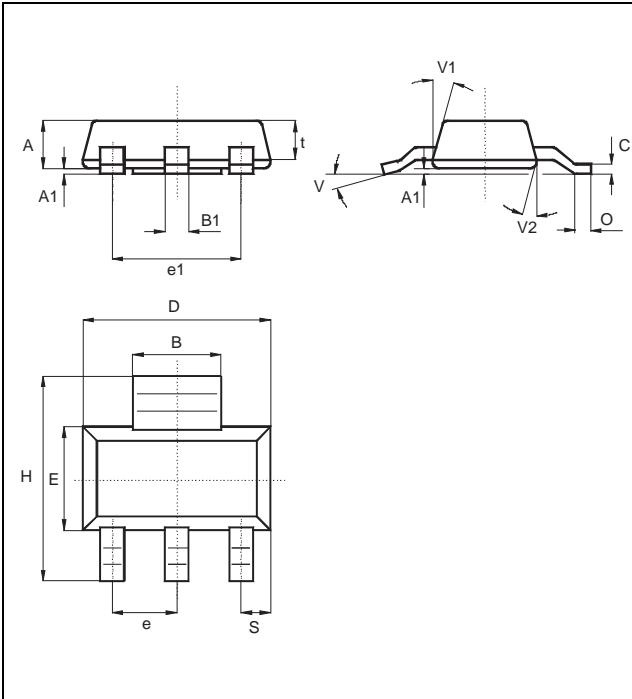


**Fig.8 :** On-state characteristics (maximum values).



## PACKAGE MECHANICAL DATA

SOT223 (Plastic)

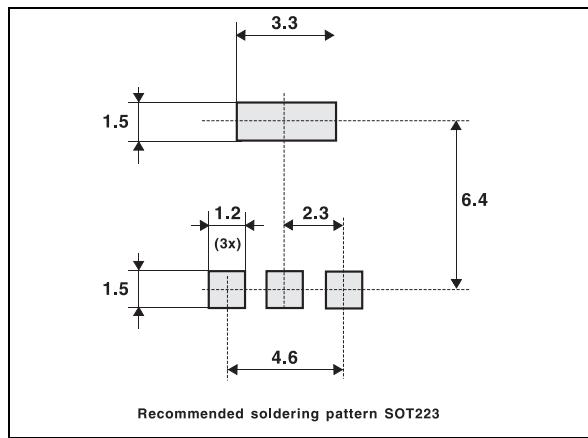


REF.	DIMENSIONS					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	1.50		1.70	0.059		0.067
A1	0.02		0.10	0.001		0.004
B	2.95		3.15	0.090		0.124
B1	0.65		0.85	0.026		0.033
C	0.25		0.35	0.010		0.014
D	6.30		6.70	0.248		0.264
e		2.3			0.091	
e1		4.6			0.181	
E	3.30		3.70	0.130		0.146
H	6.70		7.30	0.264		0.287
O	0.63	0.65	0.67	0.025	0.026	0.026
S	0.85		1.05	0.033		0.041
t	1.10		1.30	0.043		0.051
V	10° max					
V1	10° min 16°max					
V2	10° min 16°max					

Weight : 0.11 g

## MARKING

### FOOT PRINT



Type	Marking
X0202BN	X2B
X0202DN	X2D
X0202MN	X2M
X0202NN	X2N
X0203BN	X3B
X0203DN	X3D
X0203MN	X3M
X0203NN	X3N
X0205BN	X5B
X0205DN	X5D
X0205MN	X5M
X0205NN	X5N

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